

**Department of Electrical and Electronics
Engineering**

18EE501-POWER ELECTRONICS

Module I- DC to DC Converter

Topic- 1.2 Protection and Gate Drive Circuits

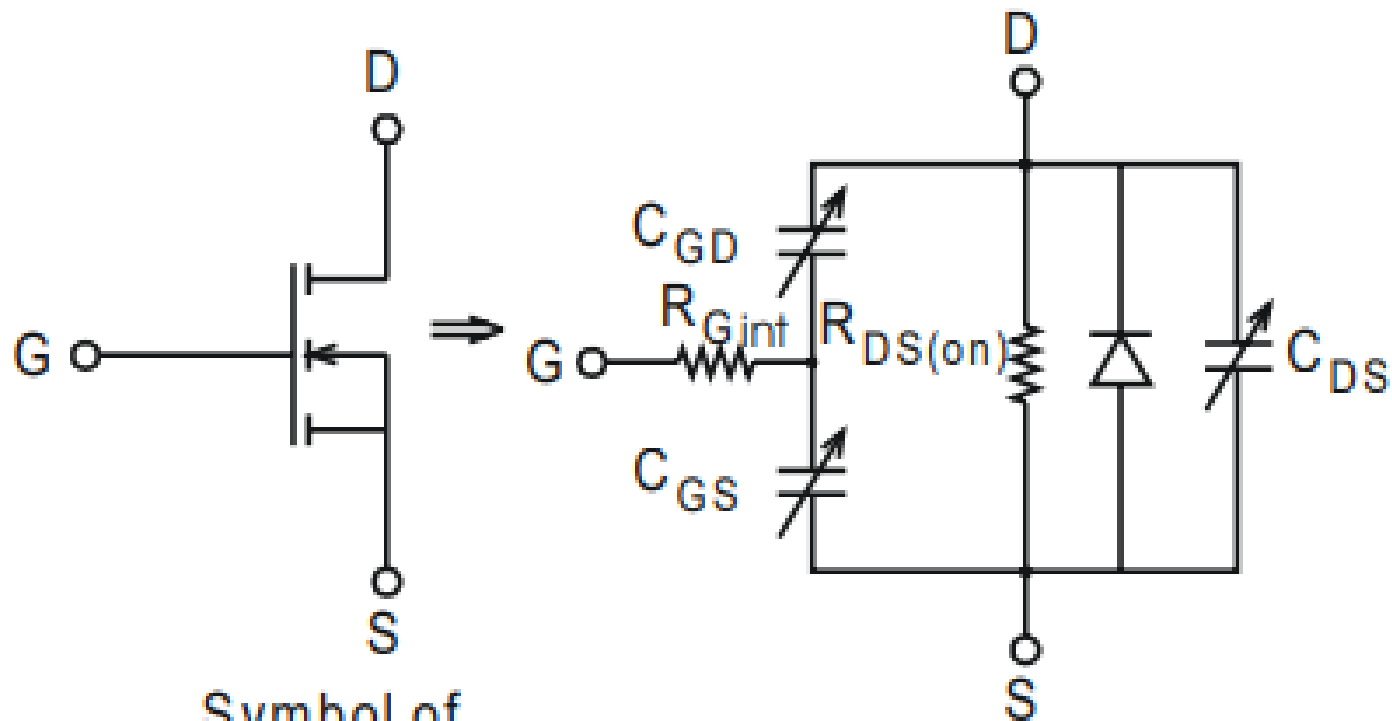
Introduction

- MOSFET Gate Driver is a specialized circuit that is used to drive the gate of power MOSFETs effectively and efficiently in high-speed switching applications.

MOSFET

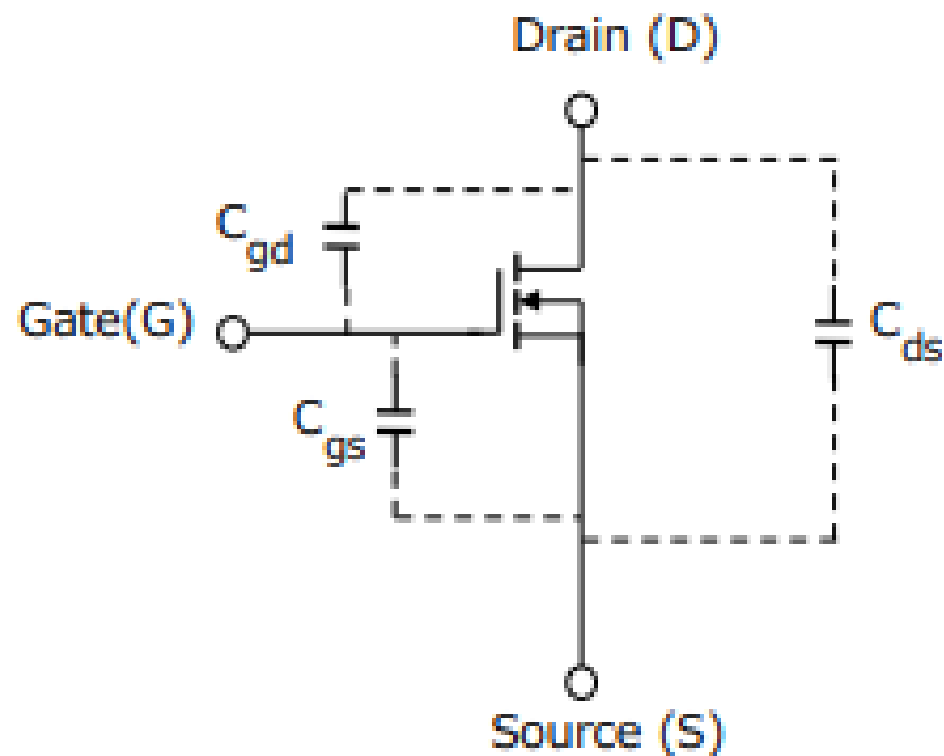
- It is the key component in high frequency, high efficiency switching applications across the electronics industry.
- It must be driven from a low impedance source capable of sourcing and sinking sufficient current to provide for fast insertion and extraction of the controlling charge

Symbol and equivalent circuit of a MOSFET



Symbol of
N-Channel MOSFET

N-Channel MOSFET and an equivalent model of the same with three inter-junction parasitic capacitances, namely: C_{GS} , C_{GD} and C_{DS}



Input capacitance $C_{iss} = C_{gd} + C_{gs}$

Output capacitance $C_{oss} = C_{ds} + C_{gd}$

Reverse Transfer capacitance $C_{rss} = C_{gd}$

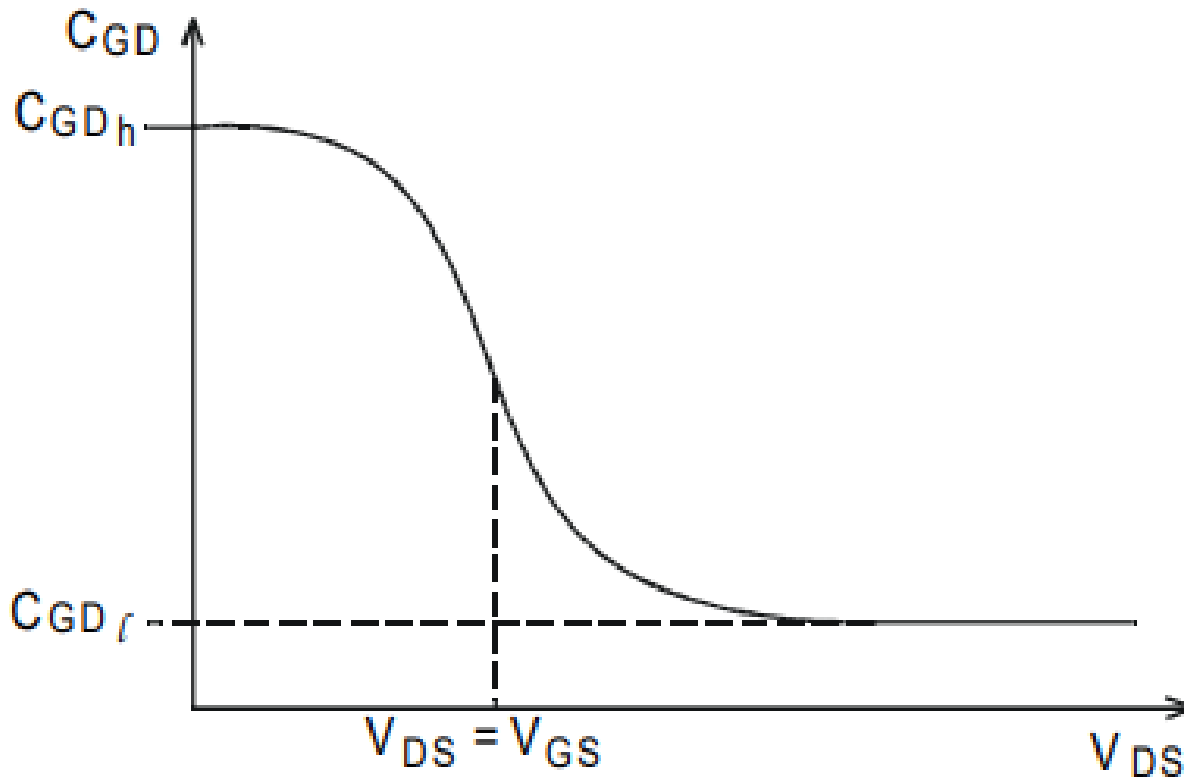
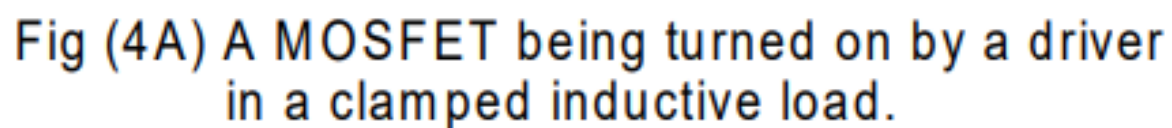


Fig. (3B) C_{GD} variation with respect to V_{DS}

the C_{GD} , decreases rapidly as the Drain to Source voltage rises, as shown in Fig
the high value of C_{GD} is called C_{GDh} , while the low value of C_{GD} is termed C_{GDl} .

- To understand Turn-on and Turn-off phenomena of the Power MOSFET, we will assume clamped inductive switching as it is the most widely used mode of operation.
- This is shown in Fig. (4A) and Fig. (4B).
- A model of MOSFET is shown with all relevant components, which play a role in turn-on and turn-off events.
- As stated above, MOSFET's Gate to Source Capacitance C_{GS} needs to be charged to a critical voltage level to initiate conduction from Drain to Source.



➤ The clamped inductive load is being shown by a current source with a diode D connected antiparallel across the inductor.

➤ The MOSFET has its intrinsic internal Gate resistance, called R_{Gint} . As described above, the inter-junction parametric capacitances (C_{GS} , C_{GD} and C_{DS}) are shown and connected at their proper points.

➤ V_{DD} represents the DC Bus voltage to the Drain of the MOSFET through the clamped inductive load.

➤ The Driver is supplied by V_{cc} of value V_p and its ground is connected to the common ground of V_{DD} and is returned to the Source of the MOSFET.

➤ The output from the Driver is connected to the Gate of the MOSFET through a resistor R_{Gext} .

➤ Now when a positive going pulse appears at the input terminal of the Driver, an amplified pulse appears at the output terminal of the Driver with an amplitude V_p .

➤ This is fed to the Gate of the MOSFET through R_{Gext} .

➤ As one can see the rate of rise of voltage, V_{GS} , over Gate and Source terminals of the MOSFET is governed by value of the total resistance in series ($R_{dr} + R_{Gext} + R_{Gint}$) and total effective value of capacitance ($C_{GS} + C_{GD}$).

➤ R_{dr} stands for the output source impedance of the Driver.

➤ R_{gext} is the resistance one generally puts in series with the Gate of a MOSFET to control the turn-on and turn-off speed of the MOSFET.

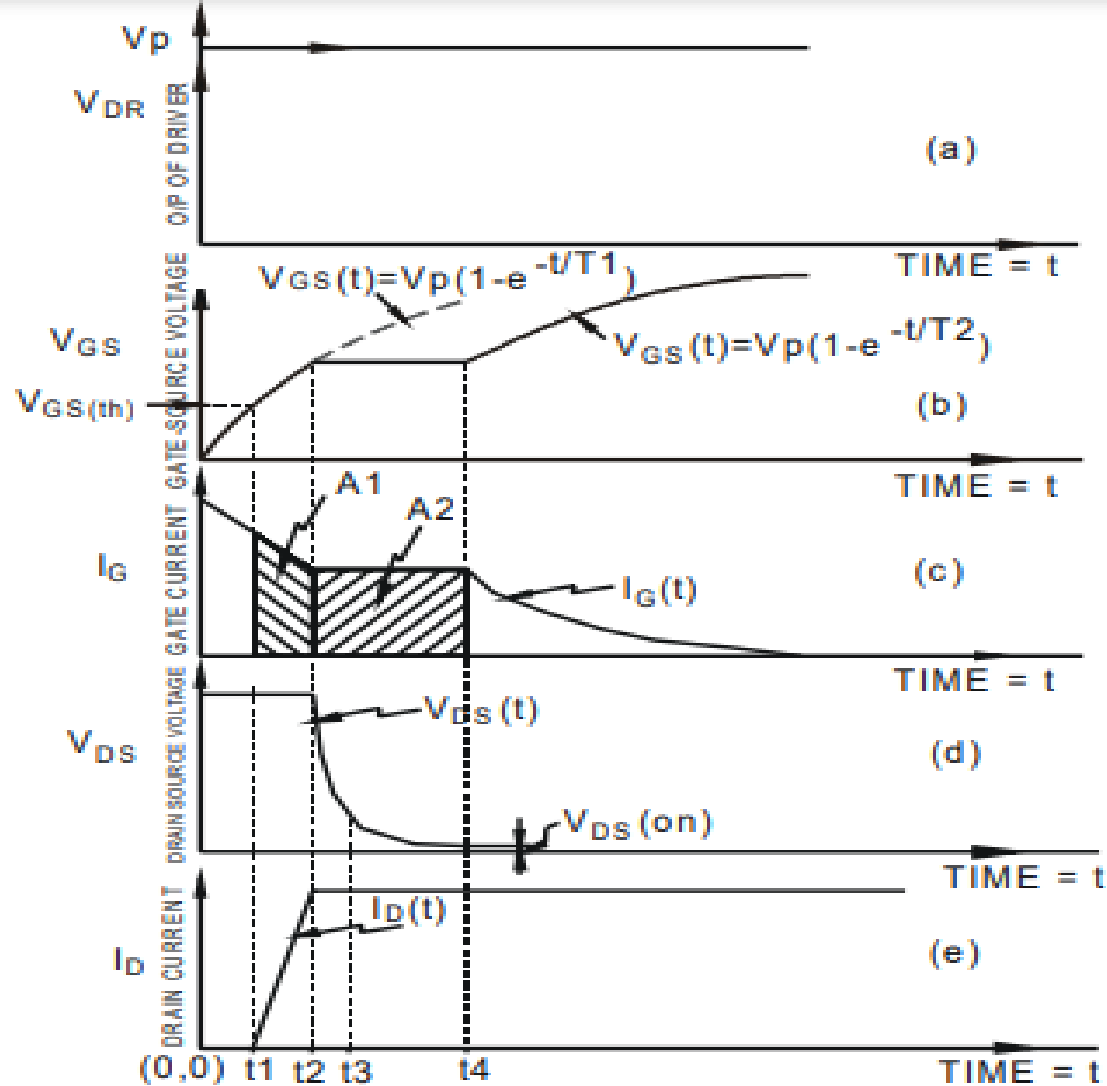


Fig. (5) MOSFET turn on sequence

The waveforms drawn in Fig. (5) show variation of different parameters with respect to time, so as to clearly explain the entire turn-on sequence.

➤ From time zero to t_1 , $(C_{GS}+C_{GD1})$ is exponentially charged with a time constant $T_1=(R_{dr}+R_{Gext}+R_{Gint}) \times (C_{GS}+C_{GD1})$, until Gate-to-source voltage reaches $V_{GS(th)}$.

➤ In this time period, neither the Drain voltage nor the Drain current are affected, i.e. Drain voltage remains at V_{DD} and Drain current has not commenced yet.

➤ This is also termed turn-on delay. Note that between 0 to t_1 , as V_{GS} rises, I_{GS} falls exponentially, more or less like a mirror image of V_{GS} , because from the point of view of circuit analysis, it is an RC Circuit.

- After time t_1 , as the Gate-to-Source voltage rises above $V_{GS(th)}$, MOSFET enters linear region
- At time t_1 , Drain current commences, but the Drain to Source voltage V_{DS} is still at V_{DD} .
- However, after t_1 , I_D builds up rapidly.
- As can be seen in Fig. (3B), from time t_1 to t_2 , C_{GD} increases from C_{GD1} to C_{GDh} and current available from the Driver is diverted to charge this increased value of C_{GDh} .

➤ Between t_1 and t_2 , the Drain current increases linearly with respect to V_{GS} .

➤ At time t_2 , the Gate to Source voltage enters the Miller Plateau level.

➤ At time t_2 , the Drain voltage begins to fall rapidly, while the MOSFET is carrying full load current.

➤ During the time interval, t_2 to t_4 , V_{GS} remains clamped to the same value and so does I_{GS} .

➤ Beyond t_4 , V_{GS} begins to exponentially rise again with a time constant $T_2 = (R_{dr} + R_{Gext} + R_{Gint}) \times (C_{GS} + C_{GDh})$.

➤ During this time interval the MOSFET gets fully enhanced, the final value of the V_{GS} determining the effective $R_{DS(on)}$.

➤ When V_{GS} reaches its ultimate value, V_{DS} attains its lowest value, determined by $V_{DS} = I_{DS} \times R_{DS(on)}$.

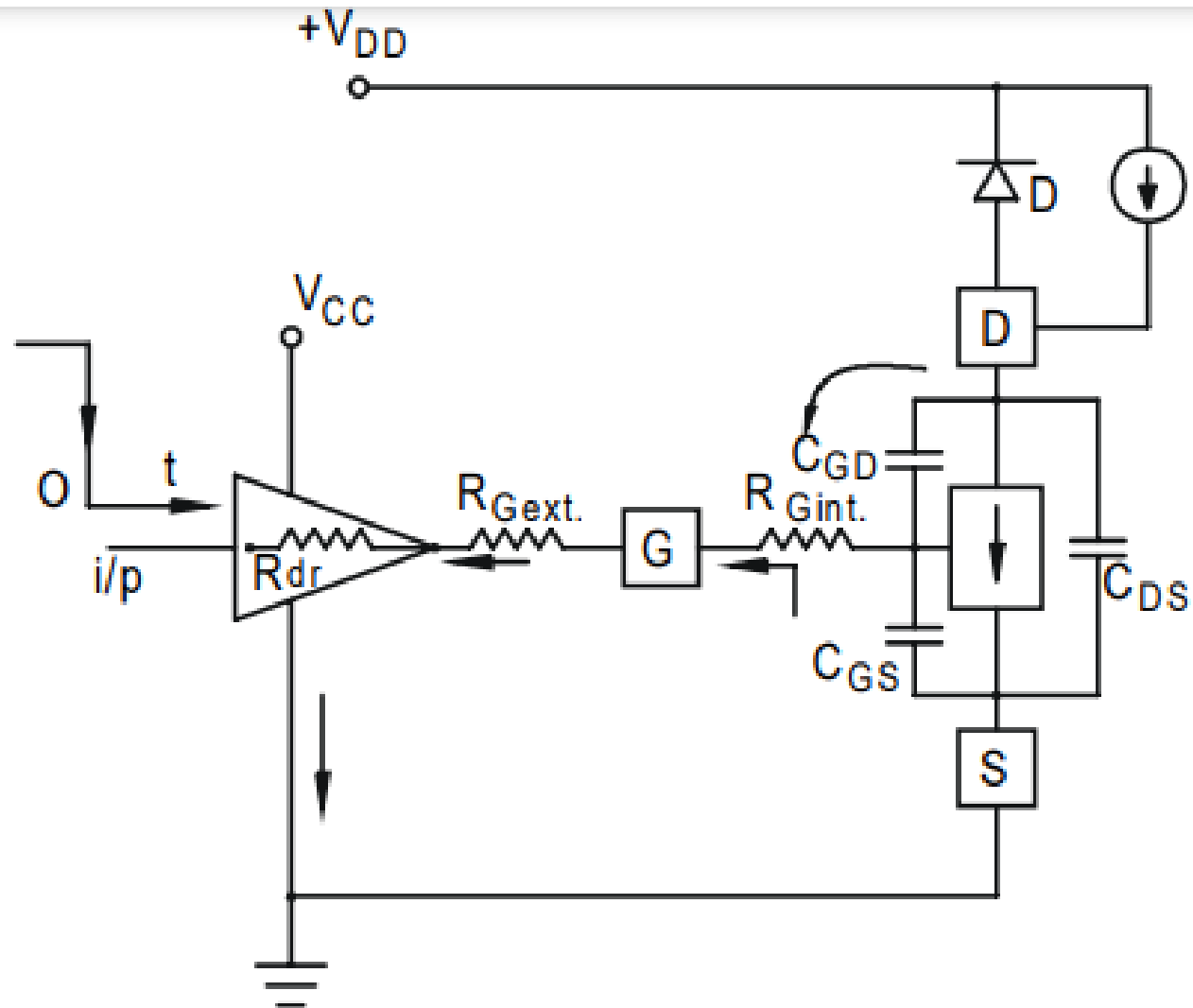


Fig. (4B) A MOSFET being turned off by a driver in a clamped inductive load.

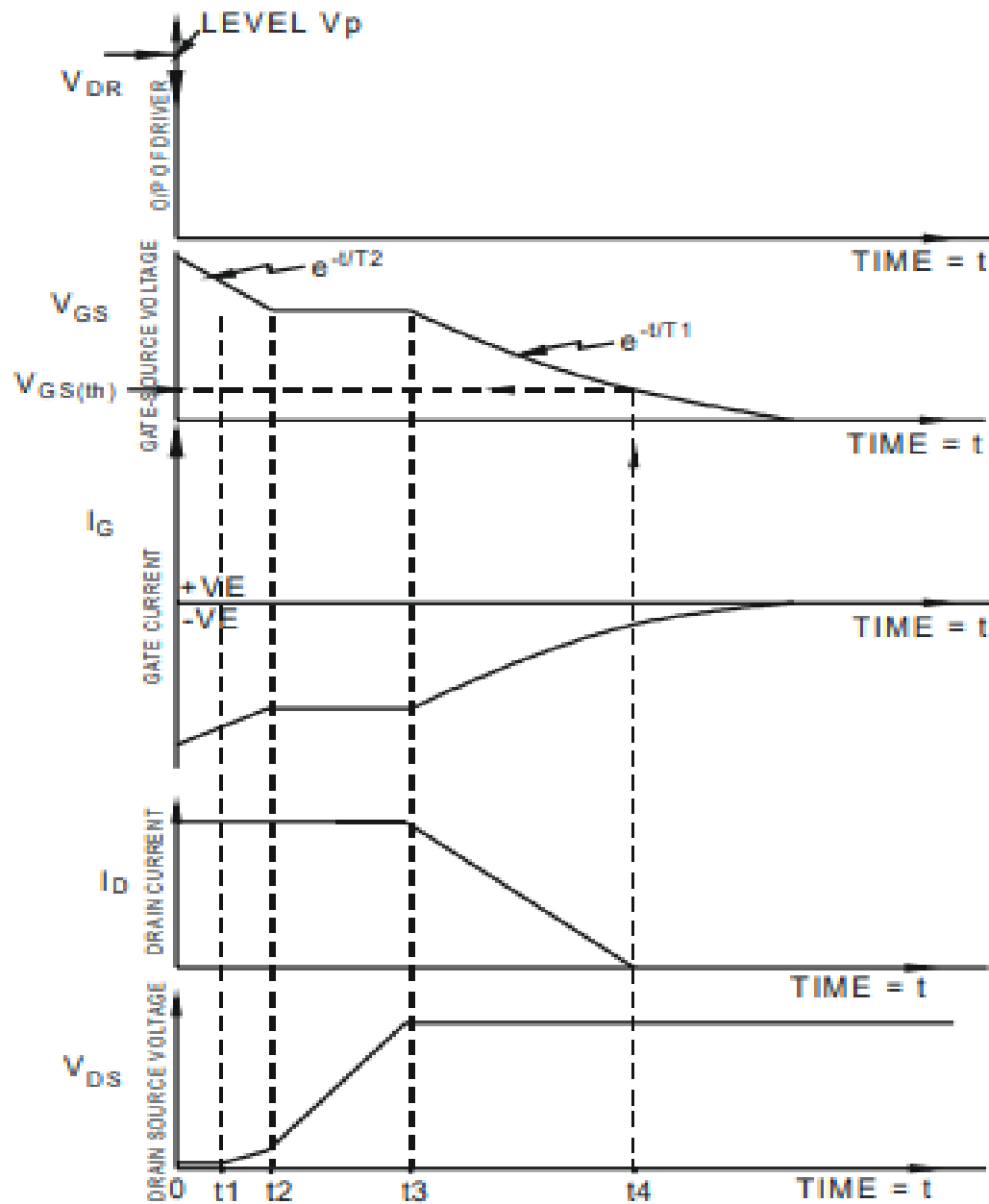


Fig. (7) MOSFET turn off sequence

- The turn-off phenomenon is shown in Fig. (7).
- As can be expected, when the output from the Driver drops to zero for turning off MOSFET, V_{GS} initially decays exponentially at the rate determined by time constant $T_2 = (R_{dr} + R_{Gext} + R_{Gint}) \times (C_{GS} + C_{GDh})$ from time 0 to t_1 ;
- however, after t_4 , it decays exponentially at the rate determined by $T_1 = (R_{dr} + R_{Gext} + R_{Gint}) \times (C_{GS} + C_{GDl})$

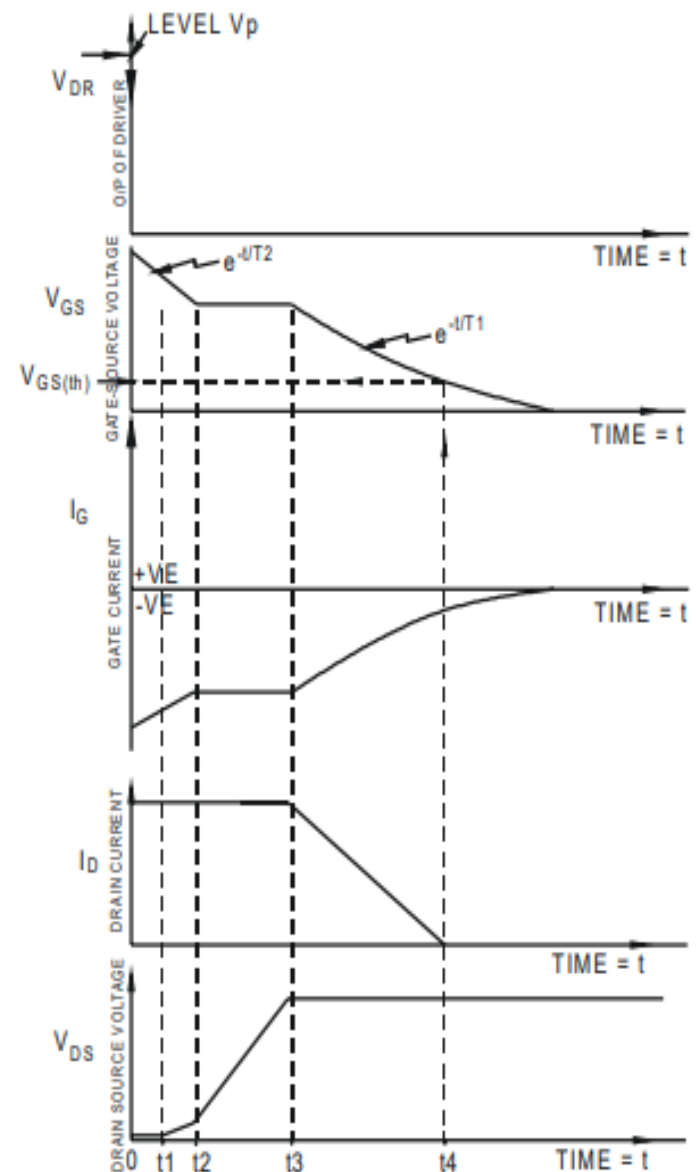
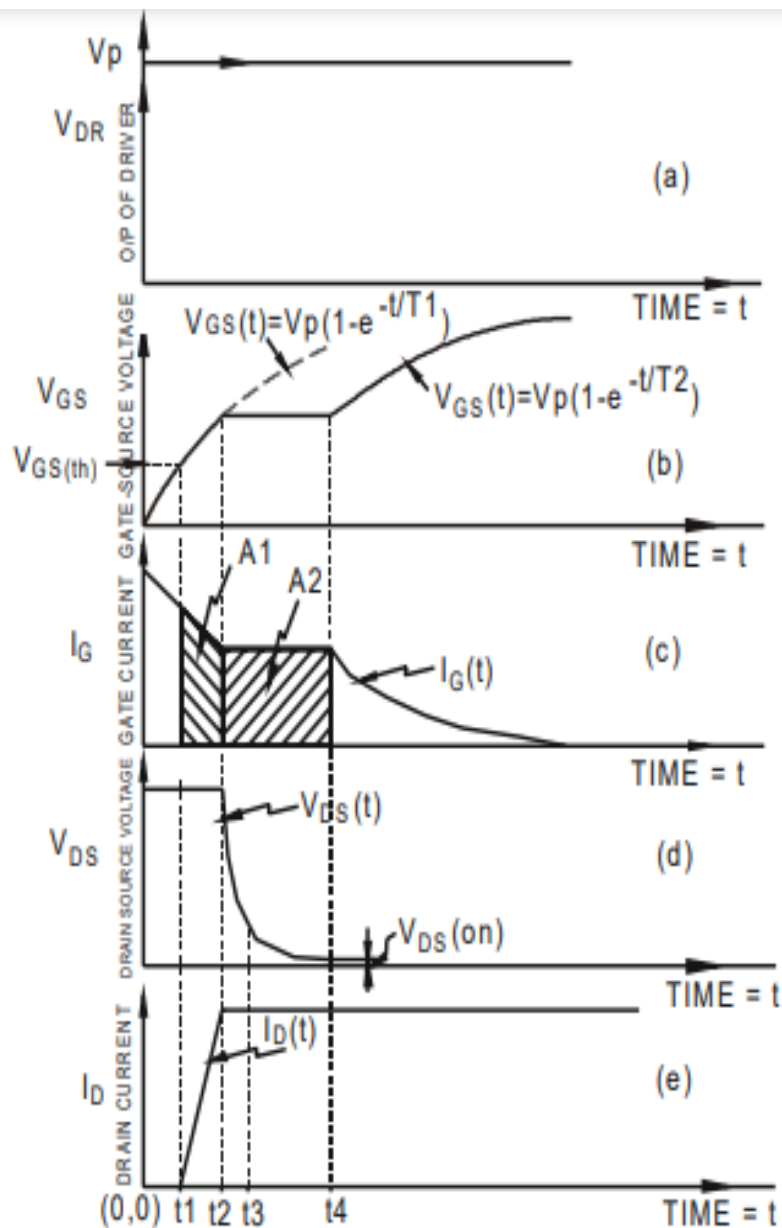
➤ From $t = 0$ to $t = t_1$, the gate current is flowing through CGS and CGD capacitances of MOSFET.

➤ Notice that the drain current I_D remains unchanged during this time interval, but the Drain Source voltage V_{DS} just begins to rise.

➤ From t_1 to t_2 , V_{DS} rises from $I_D \times R_{DS(on)}$ towards its final off state value of $V_{DS(off)}$, where it is clamped to the DC Bus voltage level by the diode in the clamped inductive switching circuit being studied.

➤ This time interval also corresponds to the Miller region as far as the gate voltage is concerned as mentioned above, which keeps V_{GS} constant

- During the next time interval, the V_{GS} begins to fall further below $V_{GS(th)}$.
- C_{GS} is getting discharged through any external impedance between Gate and Source terminals.
- The MOSFET is in its linear region and Drain current I_D drops rapidly towards zero value.
- Remember that the Drain Voltage V_{DS} was already at its off state value $V_{DS(off)}$ at the beginning of this interval.
- Thus at t_4 , the MOSFET is fully turned off.



Protection of Power semiconductor devices (SCR,MOSFET,IGBT,..)

- Power semiconductor devices need protection circuits, which are called snubber circuits, because they have a limited SOA at turn-on and turn-off transitions.
- The objective of snubber is to help the semiconductor device during switching transitions to survive the voltage and current stresses that can cause its failure.
- These stresses are caused by the interruption of the current at turn-off and the collapse of the voltage at turn-on.

Power semiconductor devices commonly protected against:

1. di/dt
2. dv/dt
3. Voltage spike or over-voltage
4. Over-current
5. Gate-under voltage
6. Overvoltage at gate
7. Excessive temperature rise
8. Electro-static discharge

➤ **di/dt Protection**

- If the rate of rise of anode current, i.e. di/dt is large as compared to the spread velocity of carriers, local hot spots will be formed near the gate connection. This localized heating may destroy the device
- The value of di/dt can be maintained below acceptable limit by using **a small inductor, called di/dt inductor in series with the anode circuit.**
- Typical di/dt limit value of SCRs are 20-500 A/ μ -sec.

➤ **dv/dt Protection**

- If the rate of rise of suddenly applied voltage across device is high, the device may get turned on. It leads to false operation of the thyristor circuits.
- Typical values of dv/dt are 20-500 V/ μ -sec.
- False turn-on of a thyristor by large dv/dt can be prevented by using a **snubber circuit** in parallel with the device.

Design of Snubber Circuits

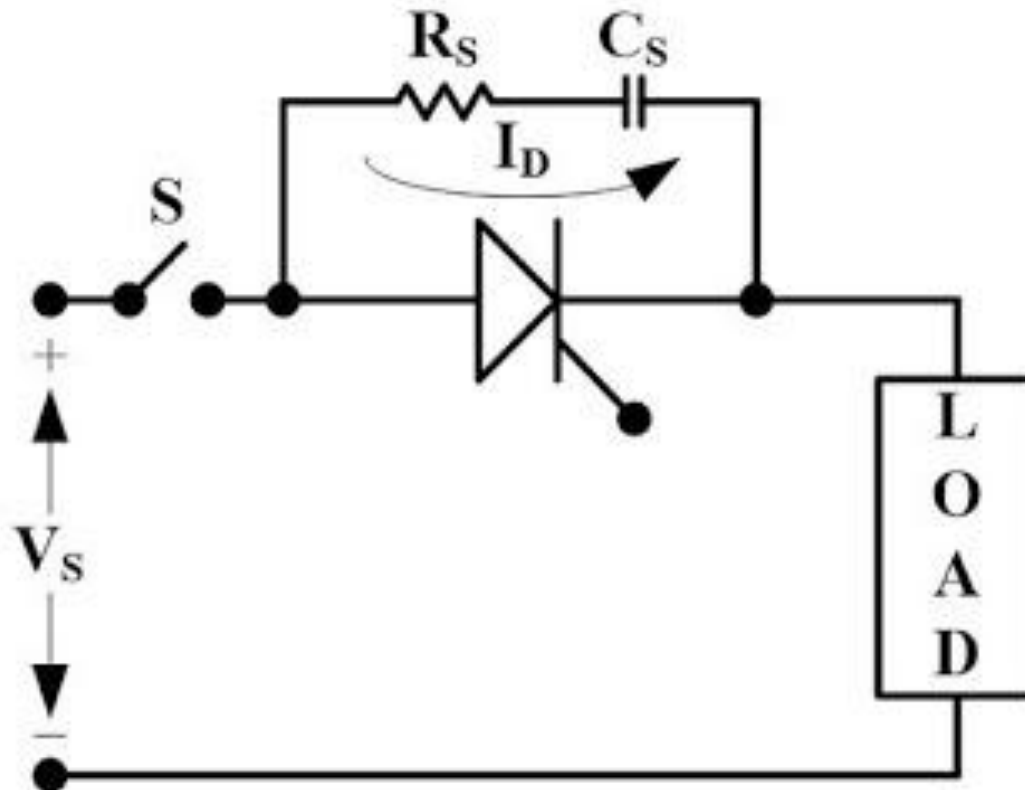


Fig. 1 Snubber Circuit across SCR

➤ When switch S is closed, a sudden voltage appears across the circuit as given in Fig. 1. Capacitor C_s behaves like a short circuit, Therefore voltage across SCR is zero.

➤ With the passage of time, Voltage across C_s builds up at a slow rate such that dv/dt across C_s and therefore across SCR is less than the specified maximum dv/dt rating.

➤ Before SCR is fired by gate pulse, C_s charges to full voltage V_s . When the SCR is turned ON, capacitor discharges through the SCR and sends a current equal to $V_s/(\text{Resistance of local path forward by } C_s \text{ and SCR})$.

- In order to limit the magnitude of discharge current I_D , a resistance R_s is inserted in series with C_s .
- In actual practice, R_s , C_s , and the load circuit parameters should be such that dv/dt across C_s during its charging is less than the specified dv/dt rating of the SCR, and discharge current at the turn ON of SCR is within reasonable limits.

Over-voltage Protection

➤ Transient over-voltages causes either maloperation of the circuit by unwanted turn-ON of a thyristor or permanent damage to the device due to reverse breakdown. A thyristor may be subjected to internal or external over-voltages.

➤ Large voltages may be generated internally during the commutation of a thyristor. External over-voltages are caused due to the interruption of current flow in an inductive circuit and also due to lightening strokes on the lines feeding the thyristor system.

➤ The effect of over-voltages is usually minimized by using RC circuits and non-linear resistors called voltage clamping device (Varistors)

Over-current Protection

- Over-current protection is achieved by the use of **circuit breakers (CB)** and fast acting fuse.
- A circuit breaker has long tripping time, Therefore generally it is used against surge currents of long duration.
- A **fast acting current limiting fuse (FACLF)** is used against a large surge currents of very short duration.
- The tripping time of CB and the fusing time of FACLF must be properly coordinated with the rating of device

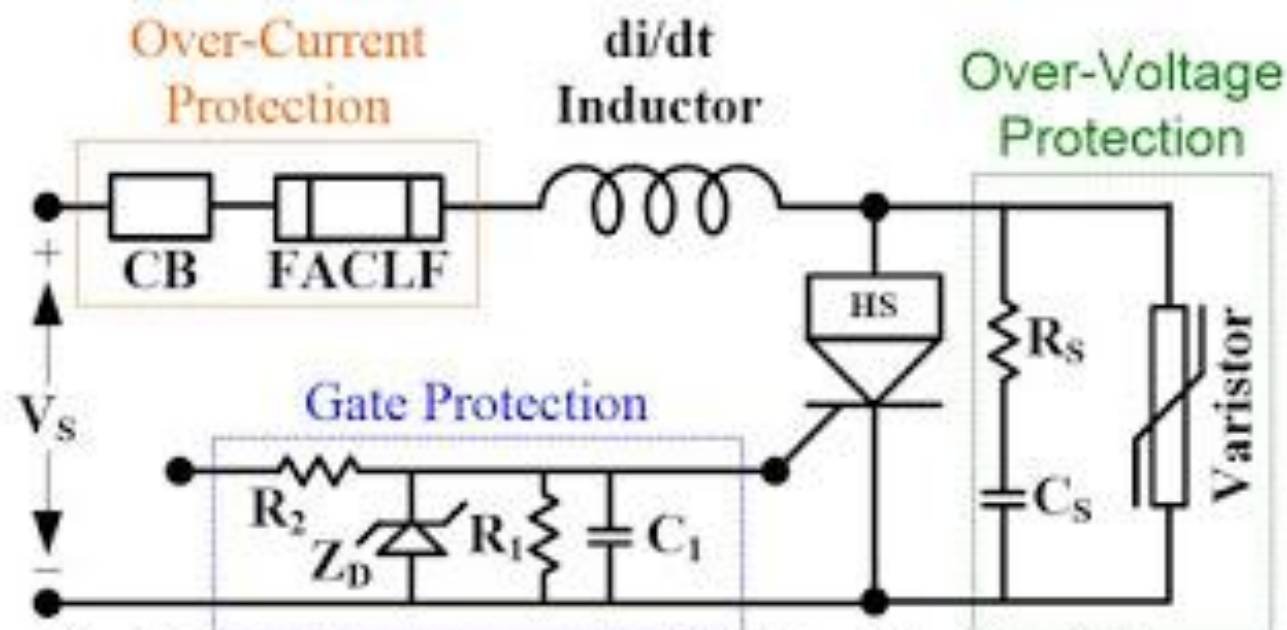


Fig. 3 Circuit components showing the Thyristor protection.

(CB: Circuit Breaker, FACLF: Fast acting current limiting fuse, HS: Heat Sink, and ZD: Zener diode)

Gate Protection

- Over-voltages across the gate circuit can cause false triggering of the SCR, while Over-current may raise junction temperature beyond specified limit leading to its damage.
- Protection against over-voltages is achieved by connecting a zener diode (ZD) across the gate circuit as given in Fig. 3. A resistor R2 connected in series with the gate circuit provides protection against over-currents.
- Protection against undesirable firing is obtained by using shielded cables or twisted gate leads.
- A capacitor and a resistor are also connected across gate to cathode to bypass the noise signals. ($C < 0.1\mu\text{F}$)

ASSESSMENT

Technical Quiz:

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Assignment:

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THANK

YOU